

[54] **VIEWER ATTACHMENT FOR A MICROSCOPE**

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[**] **Term: 14 Years**

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[58] **Field of Search D16/130-137; 350/502, 507, 508, 516, 571, 145**

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[57] **CLAIM**

The ornamental design for a viewer attachment for a microscope, as shown.

DESCRIPTION

FIG. 1 is a right side elevational view of the viewer attachment for a microscope showing my new design; FIG. 2 is a front elevational view thereof; FIG. 3 is a rear elevational view thereof; FIG. 4 is a left side elevational view thereof; FIG. 5 is a top plan view thereof; and FIG. 6 is a bottom plan view thereof.

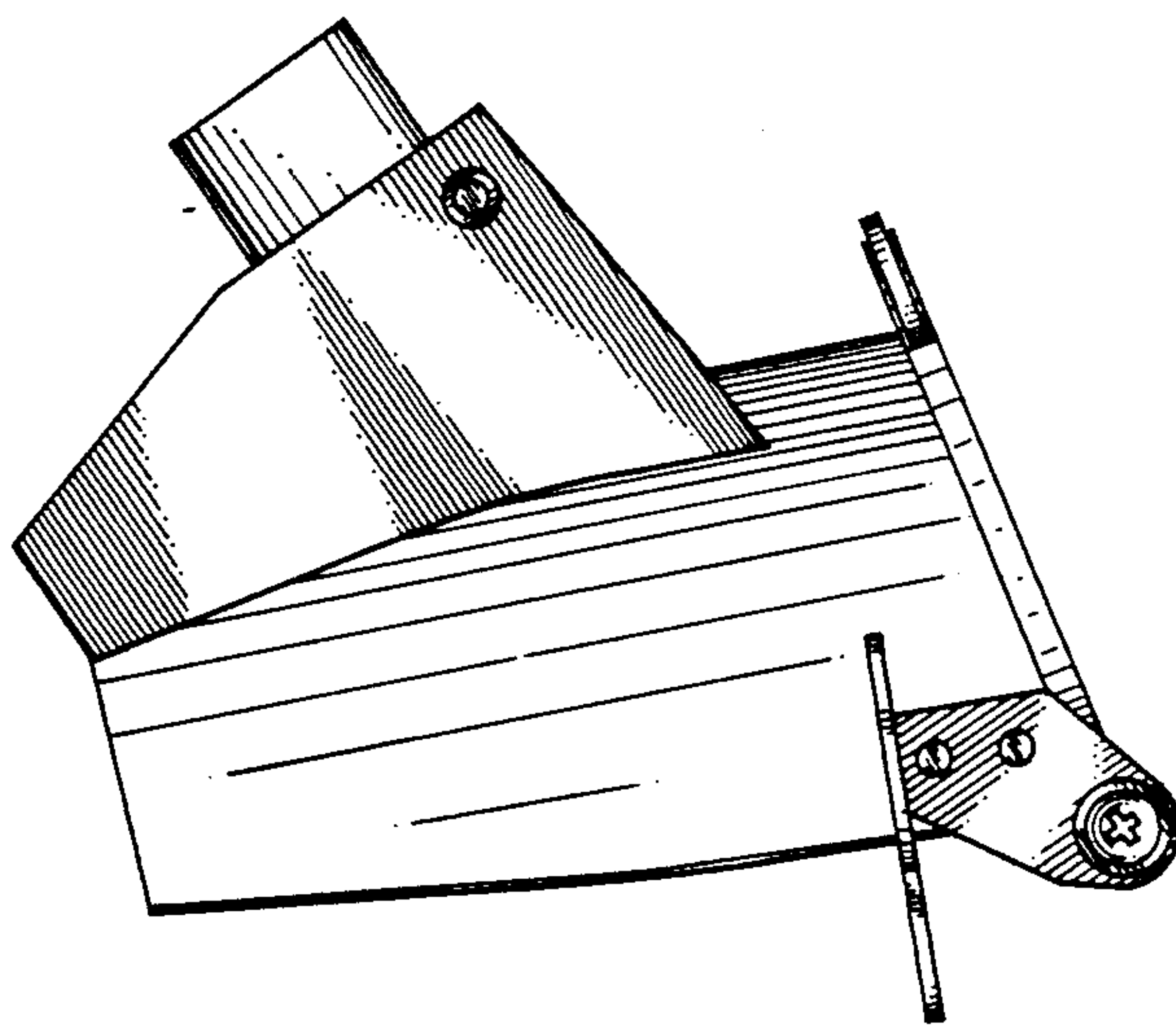


Fig. 2

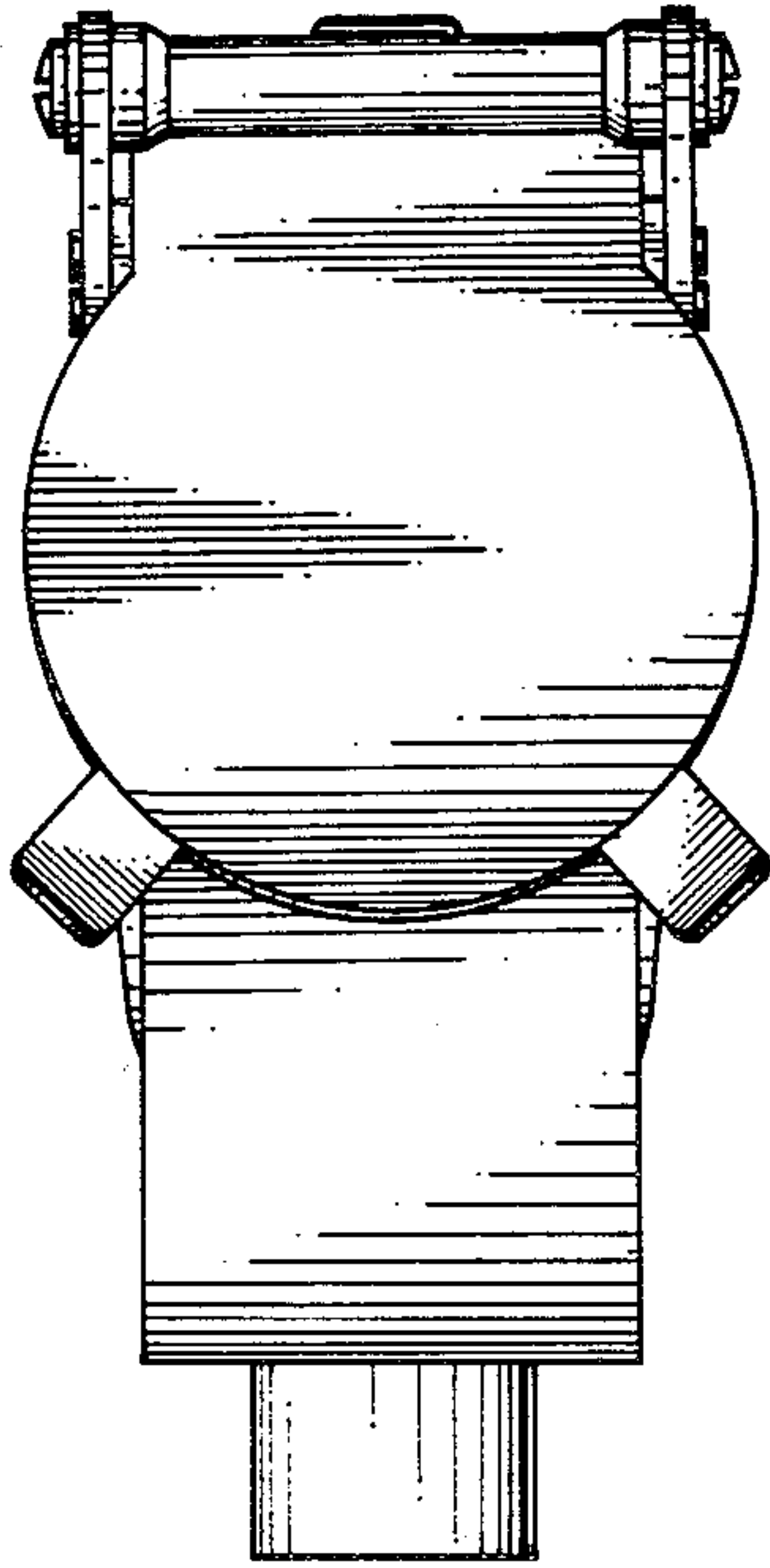


Fig. 1

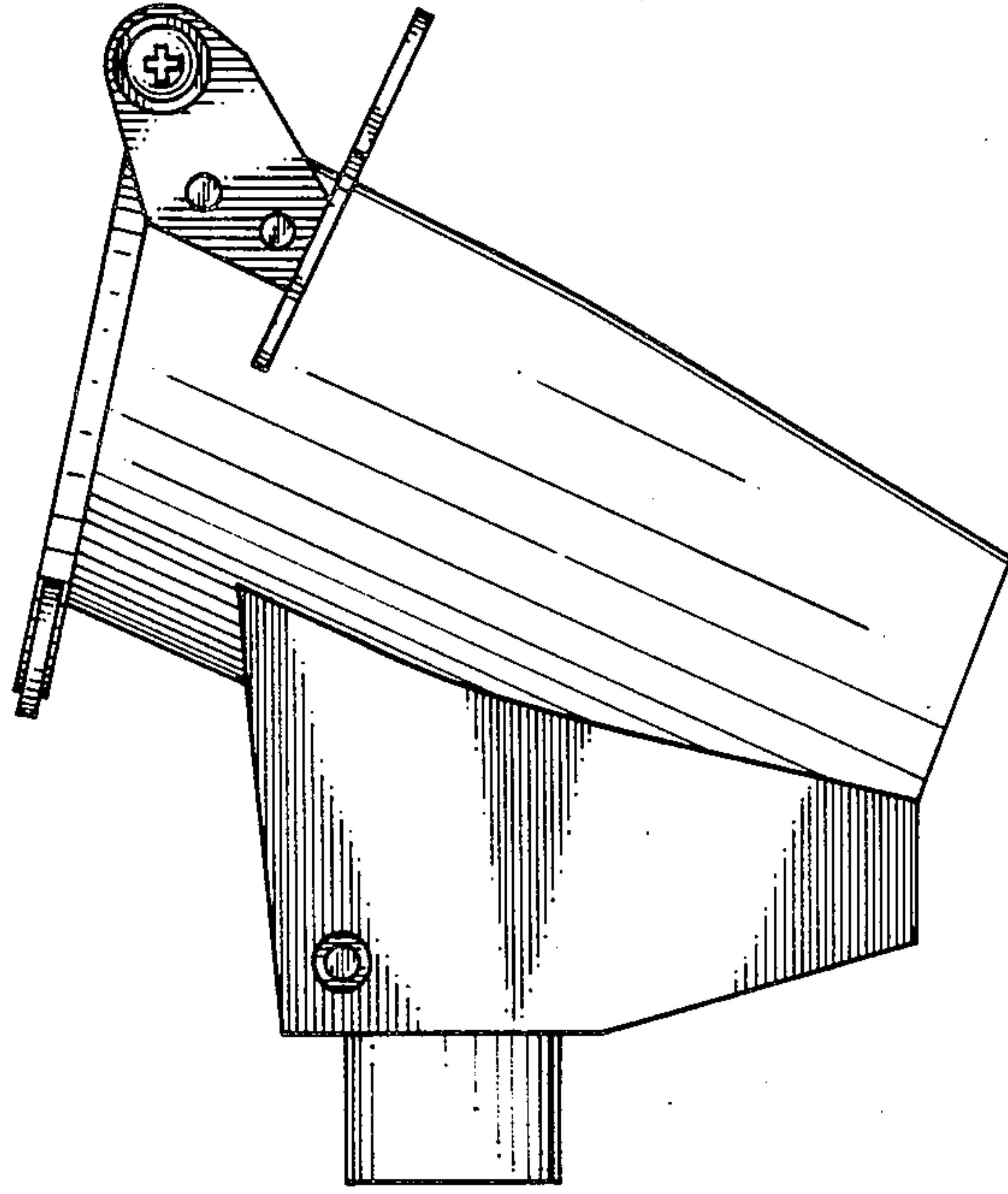


Fig. 4

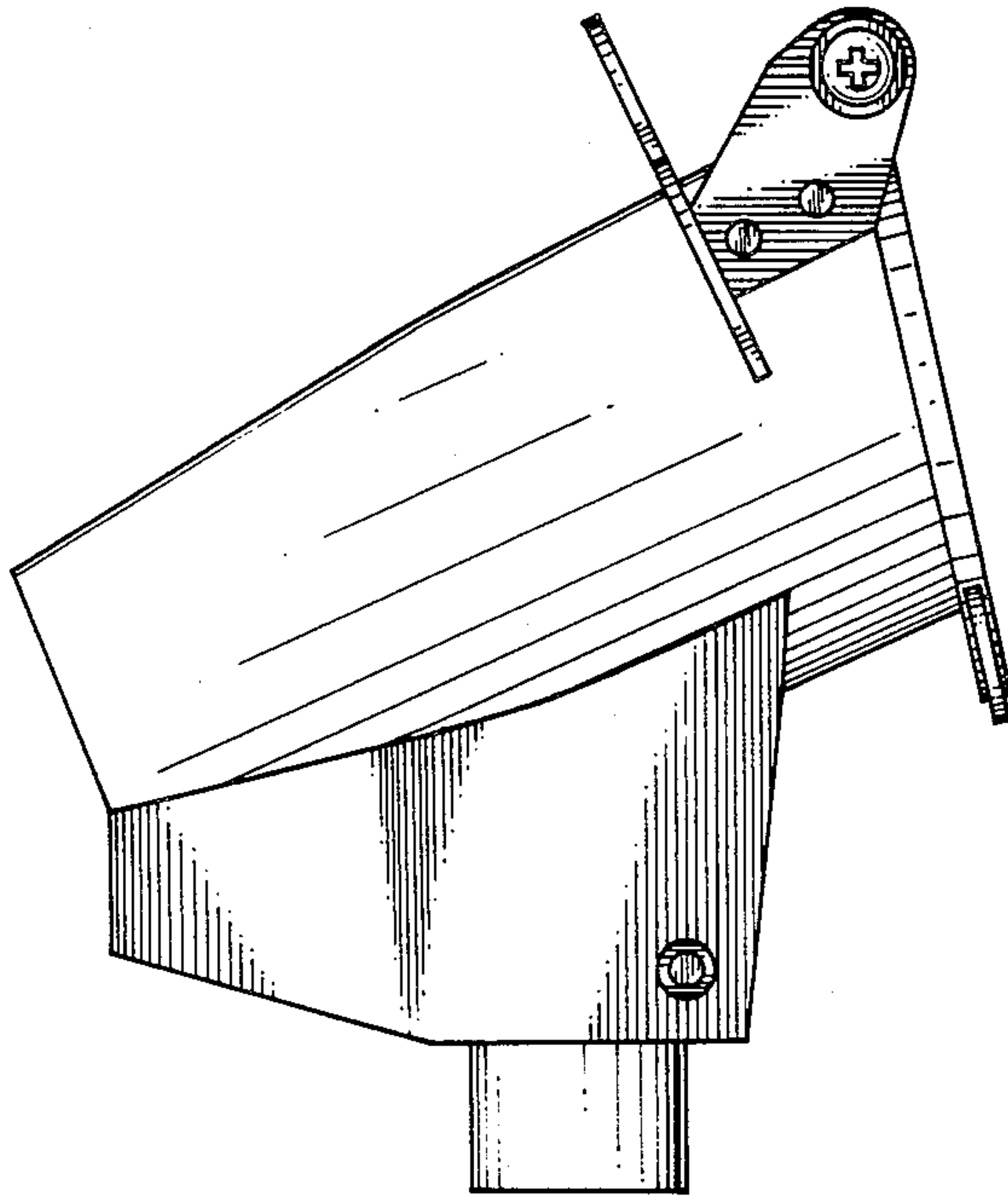


Fig. 3

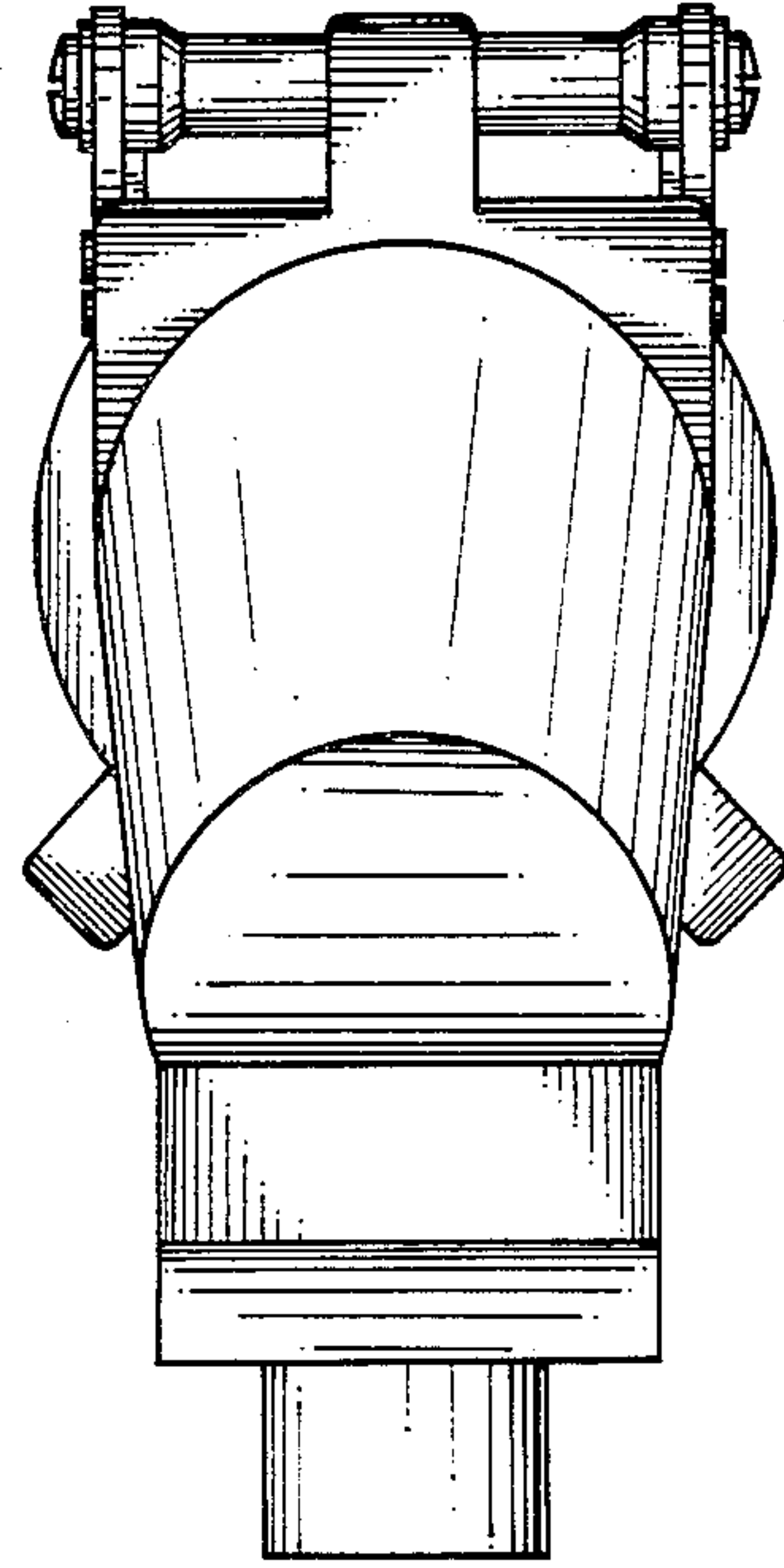


Fig. 6

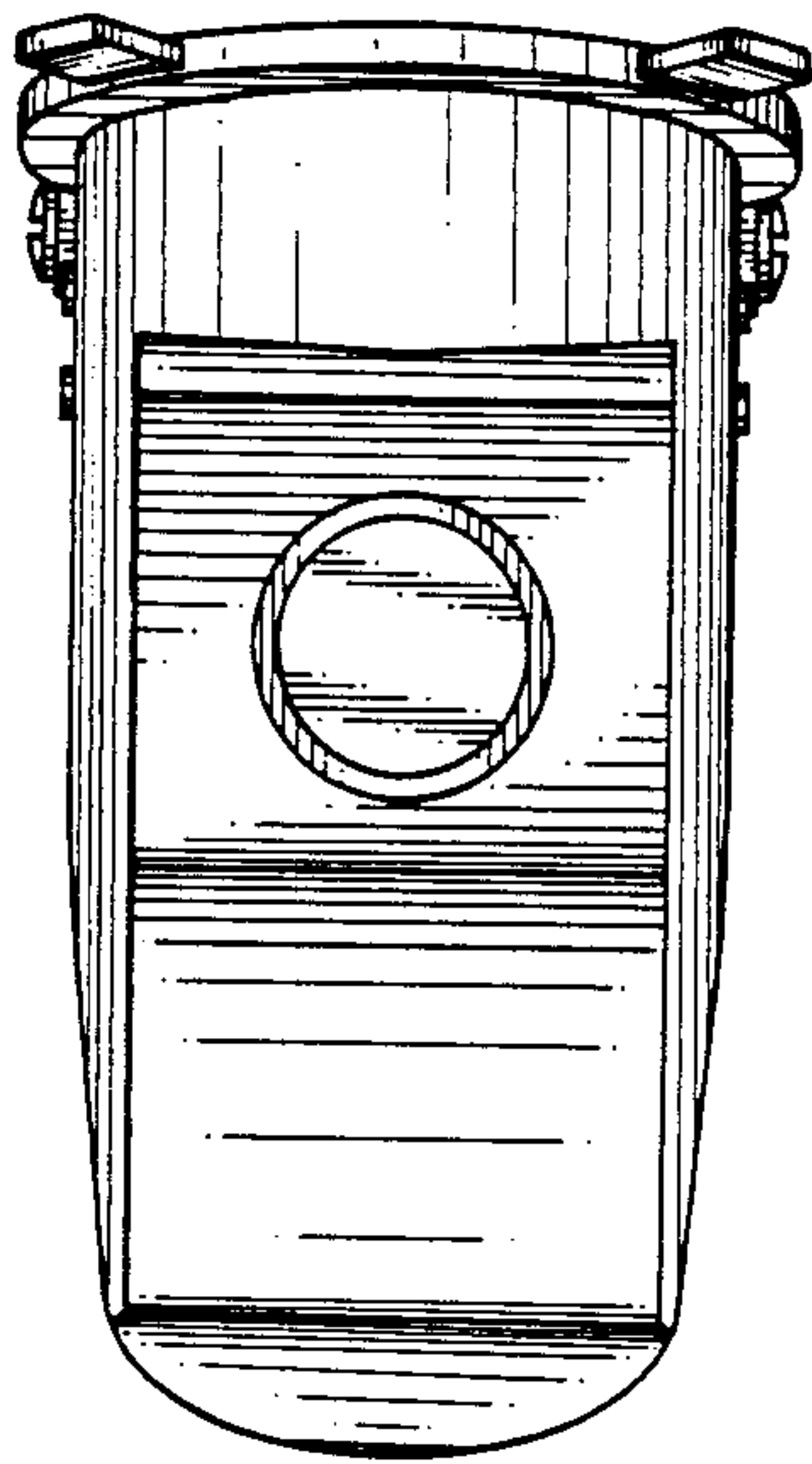


Fig. 5

